

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Naofumi NAKAMURA et al.
U.S. Serial No. : Not Yet Assigned
Filing Date : January 7, 2004
For : ***SEMICONDUCTOR DEVICE AND METHOD OF
FABRICATING THE SAME***
Group Art Unit : Not Yet Assigned

745 Fifth Avenue
New York, New York 10151

EXPRESS MAIL

Mailing Label Number: EV205872518US

Date of Deposit: January 7, 2004

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" Service under 37 CFR 1.10 on the date indicated above and is addressed to: **Mail Stop Patent Application, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.**

CHARLES JACKSON
(Typed or printed name of person mailing paper or fee)

Charles Jackson
(Signature of person mailing paper or fee)

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

The Examiner's attention is respectfully invited to review the following enclosed and listed documents which are also listed on the accompanying Form PTO-1449, enclosed in duplicate.

U.S. PATENT DOCUMENTS

1. U.S. Patent No. 5,966,634, Issued: October 12, 1999, to Inohara et al.

OTHER REFERENCES

1. Y. Igarashi et al., "*Electromigration Properties of Copper-Zirconium Alloy Interconnects*," J. VAC. SCI. TECHNOL., B 16(5), September/October 1998, pp. 2745-2750.
2. S. Varadarajan et al., "*Understanding and Reducing Copper Defects*," SEMICONDUCTOR INTERNATIONAL, June 2002, pp.125 *et seq.*

REMARKS

Pursuant to Rule 37 C.F.R. §1.97(b)(3), an Information Disclosure Statement shall be considered by the Patent Office filed before the mailing date of a first Office Action on the merits.

This Information Disclosure Statement is not a representation that the documents cited herein are considered most pertinent, or that a search has been undertaken, or that the cited documents are indeed prior art. The Examiner is invited to undertake an independent search. Applicants assert that the claimed invention is patentable over these documents.


Applicants respectfully request that the Examiner consider and make of record the documents cited herein and that a copy of Form PTO-1449, appropriately initialed by the Examiner, be returned to Applicants' attorney.

It is believed no fee is due, however, the Examiner is authorized to charge any deficit or credit any overpayment to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
Attorneys for Applicants

By: _____


Grace L. Pan
Registration No. 39,440
Tel. (212) 588-0800
Fax (212) 588-0500

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. 790001-2042		SERIAL NO. Not Yet Assigned	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Naofumi NAKAMURA et al.			
				FILING DATE January 7, 2004		GROUP Not Yet Assigned	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,966,634	10/12/99	Inohara et al.			

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
	AB		Y. Igarashi et al., "Electromigration Properties of Copper-Zirconium Alloy Interconnects," J. VAC. SCI. TECHNOL., B 16(5), September/October 1998, pp. 2745-2750
	AC		S. Varadarajan et al., "Understanding and Reducing Copper Defects," SEMICONDUCTOR INTERNATIONAL, June 2002, pp.125 et seq.

			EXAMINER
			DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.